

<b>Monday 4 October</b>	8:50	<b>Tutorial 1 Failure analysis</b> Michael Kögel, Sebastian Brand, Fraunhofer IMWS		10:30	Coffee break	10:50	<b>Tutorial 2 GaN power transistors,</b> Matteo Meneghini University of Padova		12:30	Lunch	14:00	<b>Conference Opening session</b>	14:20	<b>Invited Key Note</b> Philippe Latrese	15:00	<b>Invited Key Note</b> Vincent Huard	15:40	Coffee break	16:00	<b>Invited D</b> M. Uren	16:40	<b>Session D</b> Reliability of microwave devices and circuits 61, 147, 121, 140	18:00	<b>Session A1</b> Fault tolerant design improvement 18, 95, 112									
	<b>Tuesday 5 October</b>	8:20	8:30	<b>Invited E</b> Przemyslaw Jakub Gromala	9:10	<b>Session E1</b> Assembly evolution during accelerating ageing 68, 6, 16	10:10	Coffee break	10:30	<b>Session E2</b> Environmental tests 86, 55	11:10	<b>Session A2</b> Reliability in power systems 64, 124, 142	11:50	<b>Invited A</b> Martina Hommel	12:10	<b>Session A3 &amp; H</b> Reliab. assess. methods 114, 47, 102	12:30	Lunch	13:50	<b>Exhibitor Flash Presentation</b>	14:00	<b>Invited Key Note</b> Jesus Del Alamo	14:40	<b>Session F2-1</b> Wide bandgap degradation physics 115, 32, 104, 100	16:00	<b>Session B1</b> Reliability in MOS Techno: Low Voltage to High Power 152, 90, 120, 53	16:20	Coffee break	16:40	<b>Invited F2</b> Shuzhen You	17:00	<b>Session F2-2</b> Wide bandgap failure analysis 82, 33, 12, 103	18:20
<b>Wednesday 6 October</b>	8:20	8:30	<b>Invited I3</b> Ruben Garcia Alia	9:10	<b>Session I3-1</b> Radiation impact on reliability 76,109, 89	10:10	Coffee break	10:30	<b>Session I3-2</b> Radiation impact on reliability 143, 59, 79, 122, 146	12:10	Lunch	13:50	<b>Exhibitor Flash Presentation</b>	14:00	<b>Invited I1- I2</b> Steven Voldman	14:40	<b>Session I1- I2</b> ESD-EOS, Latchup, EMC-EMI 88, 15, 41, 96, 127	16:20	Coffee break	16:40	<b>Poster session I</b> 9, 49, 54, 57, 63, 65, 84, 87, 94, 99, 108, 130	18:20	<b>Poster session F1, F2, F3</b> 70, 98, 21, 46, 62, 83, 125, 10, 22, 36, 39, 43, 56, 66										
<b>Thursday 7 October</b>	8:20	8:30	<b>Invited G</b> Thomas Geernaert	9:10	<b>Session G</b> Photonic reliability 13, 97, 117, 126, 148	10:50	Coffee break	11:10	<b>Poster session G, B, C</b> 45, 11, 50, 135, 20, 25	12:10	Lunch	13:50	<b>Exhibitor Flash Presentation</b>	14:00	<b>Invited C</b> Konstantin Schektihin	14:40	<b>Session C</b> Progress in failure analysis 93, 136, 37, 110, 141	16:20	Coffee break	17:00	<b>Photonic Workshop</b>	17:40	<b>BPA Announcement and Closing</b>										